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Applicati n Number	09/759,414		
Filing Date	01-13-2001		
First Named Invent r	LI, ZHE		
Group Art Unit	2123		
Examiner Name	TESKA, KEVIN-J-		
Attorney Docket Number			

Tom Stevens

		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS		:
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²	
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